

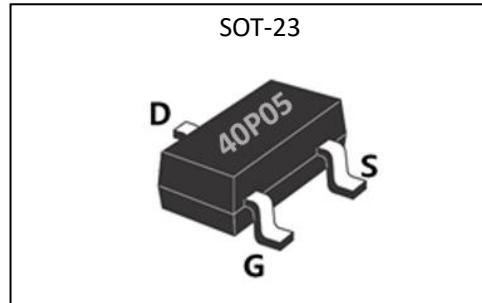
**GL Silicon P-Channel Power MOSFET**
**General Description :**

The GL5P04 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications. The package form is SOT-23-3L, which accords with the RoHS standard.

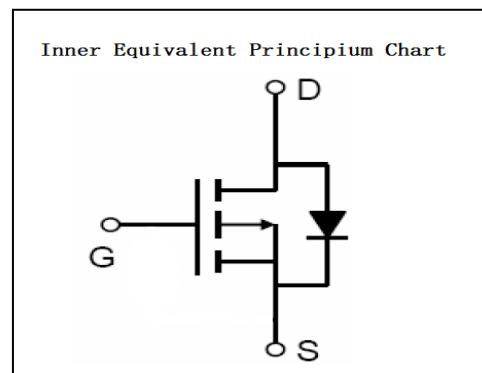
$V_{DSS}$	-40	V
$I_D$	-5	A
$P_D$	2.0	W
$R_{DS(ON)}\text{type}$	75	$\text{m}\Omega$

**Features :**

- $R_{DS(ON)} < 85 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$  (Typ 75 mΩ)
- High density cell design for ultra low  $R_{ds(on)}$
- Fully characterized avalanche voltage and current
- Excellent package for good heat dissipation


**Applications :**

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply


**Absolute (  $T_c = 25^\circ\text{C}$  unless otherwise specified ) :**

Symbol	Parameter	Rating	Units
$V_{DSS}$	Drain-to-Source Voltage	-40	V
$I_D$	Continuous Drain Current	-5.3	A
$I_{DM}$	Pulsed Drain Current	-3.7	A
$V_{GS}$	Gate-to-Source Voltage	$\pm 20$	V
$P_D$	Power Dissipation	2.0	W
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	150, -55 to 150	°C

**GL Silicon P-Channel Power MOSFET**
**Electrical Characteristics ( T<sub>C</sub>= 25°C unless otherwise specified ) :**

OFF Characteristics						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
V <sub>DSS</sub>	Drain to Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	-40	--	--	V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>DS</sub> =-40V, V <sub>GS</sub> = 0V, T <sub>a</sub> =25°C	--	--	-1.0	μA
I <sub>GSS(F)</sub>	Gate to Source Forward Leakage	V <sub>GS</sub> =+20V	--	--	0.1	μA
I <sub>GSS(R)</sub>	Gate to Source Reverse Leakage	V <sub>GS</sub> =-20V	--	--	-0.1	μA

ON Characteristics <sup>a3</sup>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
R <sub>DSON</sub>	Drain-to-Source On-Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-5A	--	75	85	mΩ
V <sub>GTH</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	-1.0	--	-3.0	V

Pulse width tp≤380μs, δ≤2%

Dynamic Characteristics <sup>a4</sup>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =-15V, I <sub>D</sub> =-4A	8	--	--	S
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =-20V	--	600	--	pF
C <sub>oss</sub>	Output Capacitance	f=1.0MHz	--	90	--	
C <sub>rss</sub>	Reverse Transfer Capacitance		--	70	--	

Resistive Switching Characteristics <sup>a4</sup>						
Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
t <sub>d(ON)</sub>	Turn-on Delay Time	V <sub>DD</sub> =-20V, R <sub>L</sub> =2Ω	--	9	--	ns
t <sub>r</sub>	Rise Time		--	8	--	
t <sub>d(OFF)</sub>	Turn-Off Delay Time		--	28	--	
t <sub>f</sub>	Fall Time		--	10	--	
Q <sub>g</sub>	Total Gate Charge	V <sub>DD</sub> =-20V, I <sub>D</sub> =-4A	--	14	--	nC
Q <sub>gs</sub>	Gate to Source Charge		--	2.9	--	
Q <sub>gd</sub>	Gate to Drain ( "Miller" )Charge		--	3.8	--	

**GL Silicon P-Channel Power MOSFET**
**Source-Drain Diode Characteristics**

Symbol	Parameter	Test Conditions	Rating			Units
			Min.	Typ.	Max.	
$I_S$	Continuous Source Current <sup>a2</sup> (Body Diode)		--	--	-5.3	A
$V_{SD}$	Diode Forward Voltage <sup>a3</sup>	$I_S = -5.3A, V_{GS} = 0V$	--	--	-1.2	V

Symbol	Parameter	Typ.	Units
$R_{eJC}$	Junction-to-Case <sup>a2</sup>	83.3	°C/W

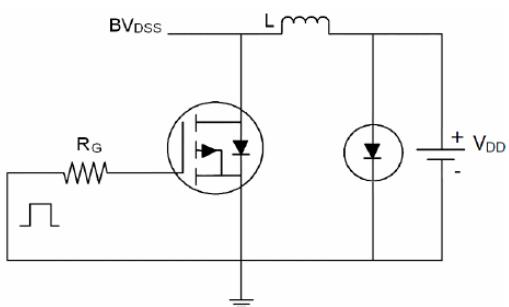
<sup>a1</sup> : Repetitive Rating: Pulse width limited by maximum junction temperature.

<sup>a2</sup> : Surface Mounted on FR4 Board,  $t \leq 10\text{sec}$ .

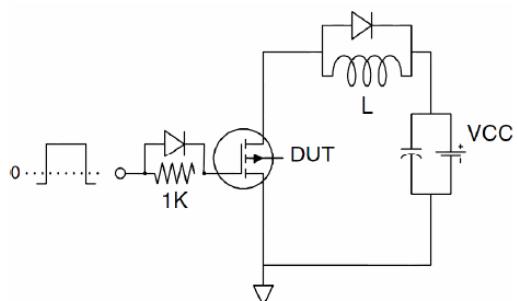
<sup>a3</sup> : Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 2\%$ .

<sup>a4</sup> : Guaranteed by design, not subject to production

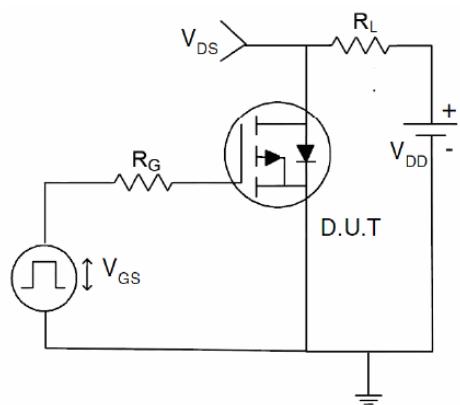
**Test circuit**

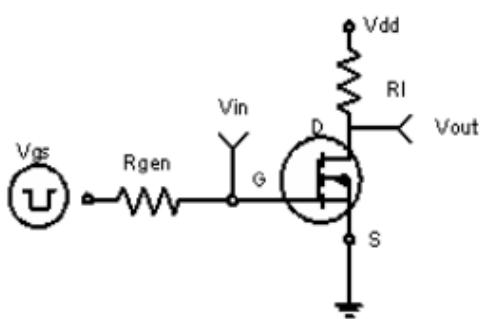
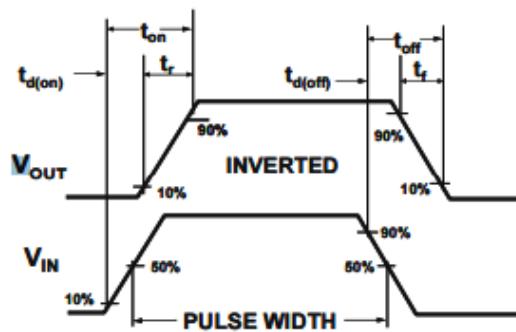
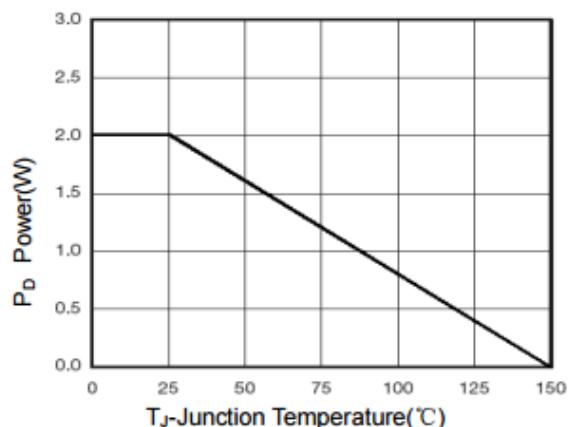
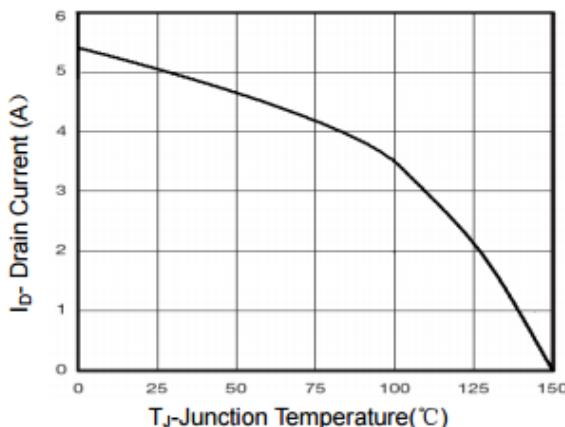
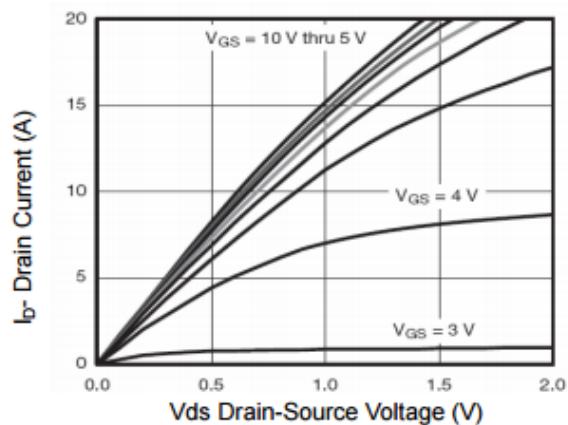
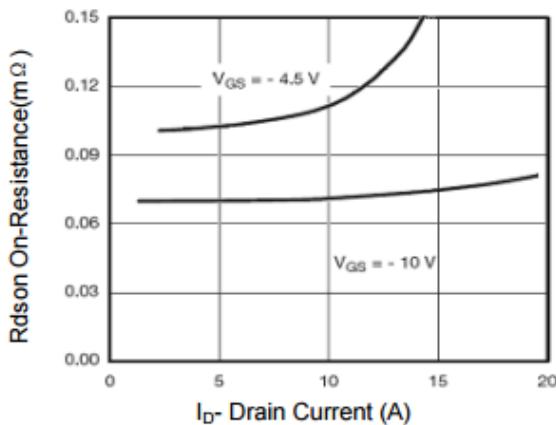
 1)  $E_{AS}$  Test Circuit


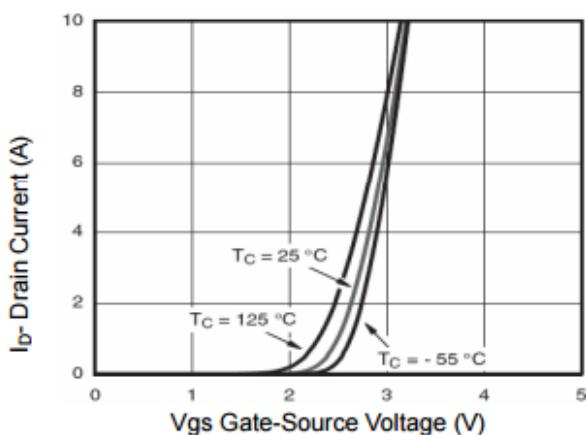
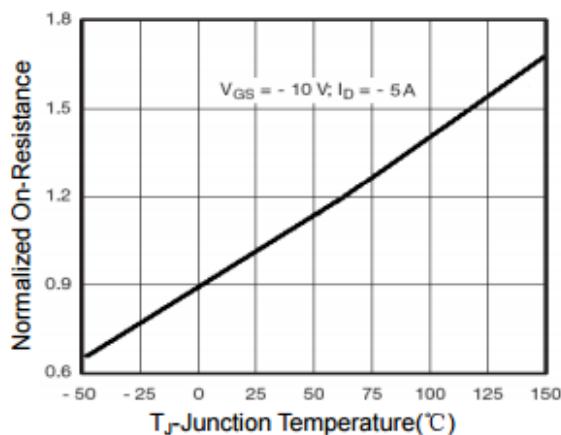
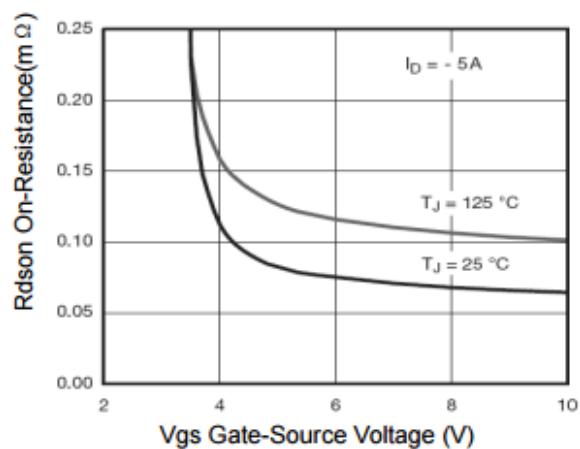
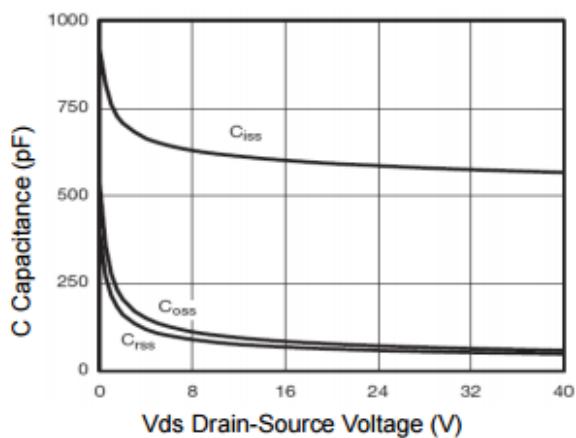
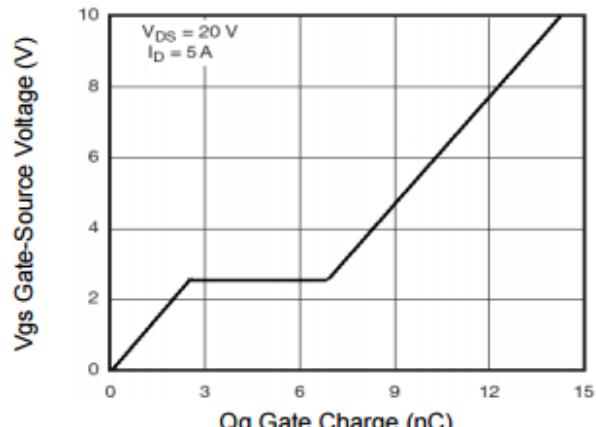
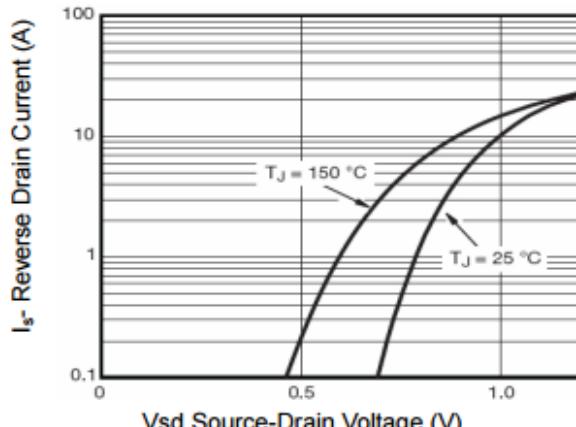
## 2) Gate Charge Test Circuit

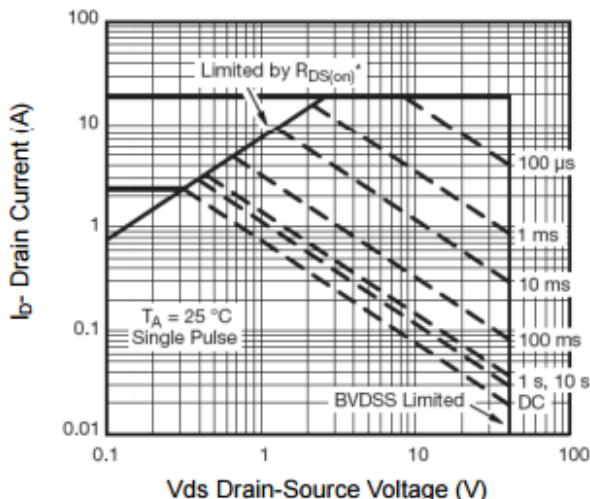
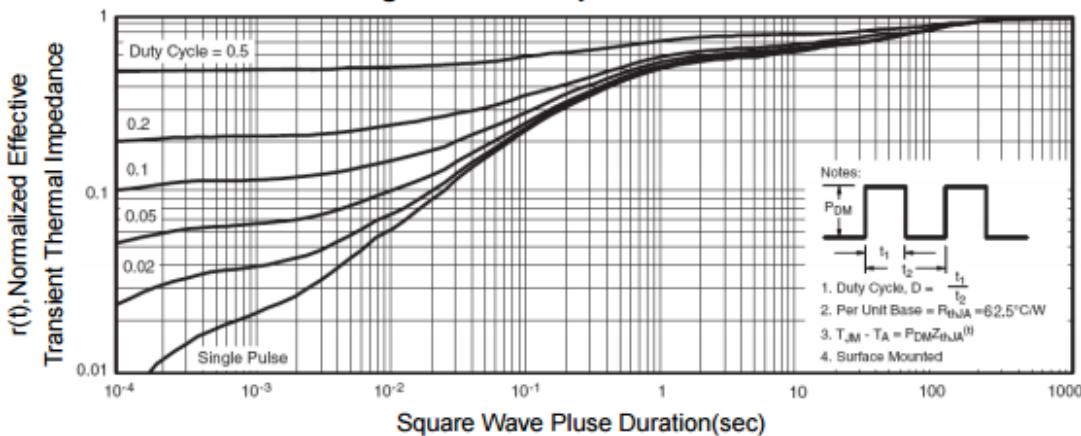


## 3) Switch Time Test Circuit



**GL Silicon P-Channel Power MOSFET**
**Typical Electrical and Thermal Characteristics**

**Figure 1:Switching Test Circuit**

**Figure 2:Switching Waveforms**

**Figure 3 Power Dissipation**

**Figure 4 Drain Current**

**Figure 5 Output Characteristics**

**Figure 6 Drain-Source On-Resistance**

**GL Silicon P-Channel Power MOSFET**

**Figure 7 Transfer Characteristics**

**Figure 8 Drain-Source On-Resistance**

**Figure 9  $R_{DS(on)}$  vs  $V_{GS}$** 

**Figure 10 Capacitance vs  $V_{DS}$** 

**Figure 11 Gate Charge**

**Figure 12 Source-Drain Diode Forward**

***GL Silicon P-Channel Power MOSFET***

**Figure 13 Safe Operation Area**

**Figure 14 Normalized Maximum Transient Thermal Impedance**

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